## IPB100P03P3L-04 IPI100P03P3L-04, IPP100P03P3L-04

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

#### Thermal characteristics<sup>2)</sup>

Thermal resistance, junction - case	R <sub>thJC</sub>		-	-	0.65	K/W
Thermal resistance, junction - ambient, leaded	$R_{ m thJA}$		-	-	62	
SMD version, device on PCB	$R_{\mathrm{thJA}}$	minimal footprint	-	-	62	
		6 cm <sup>2</sup> cooling area <sup>3)</sup>	-	-	40	

#### **Electrical characteristics,** at $T_j$ =25 °C, unless otherwise specified

#### **Static characteristics**

Drain-source breakdown voltage	$V_{(BR)DSS}$	V <sub>GS</sub> =0V, I <sub>D</sub> =-250μA	-30	ı	ı	V
Gate threshold voltage	$V_{GS(th)}$	$V_{\rm DS} = V_{\rm GS}$ , $I_{\rm D} = -475 \mu \rm A$	-1	-1.5	-2.1	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{\rm DS}$ =-30V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =25°C	ı	-0.1	-1	μΑ
		$V_{\rm DS}$ =-30V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =125°C <sup>2)</sup>	-	-10	-100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =-16V, V <sub>DS</sub> =0V	-	-10	-100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-50A	1	4.8	7.6	mΩ
		$V_{\rm GS}$ =-4.5V, $I_{\rm D}$ =-50A, SMD version	1	4.5	7.3	
		V <sub>GS</sub> =-10V, I <sub>D</sub> =-80A	-	3.3	4.3	
		$V_{\rm GS}$ =-10V, $I_{\rm D}$ =-80A, SMD version	1	3.0	4	

#### IPB100P03P3L-04

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Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

#### Dynamic characteristics<sup>2)</sup>

Input capacitance	C iss		_	7150	9300	pF
Output capacitance	C oss	V <sub>GS</sub> =0V, V <sub>DS</sub> =-25V, f=1MHz	-	2150	2800	
Reverse transfer capacitance	C <sub>rss</sub>		-	1650	2500	1
Turn-on delay time	t <sub>d(on)</sub>		-	30	-	ns
Rise time	t <sub>r</sub>	$V_{\rm DD}$ =-15V, $V_{\rm GS}$ =-10V, $I_{\rm D}$ =-50A, $R_{\rm G}$ =6 $\Omega$	-	45	-	
Turn-off delay time	$t_{d(off)}$		-	200	-	
Fall time	t <sub>f</sub>	]	-	180	-	

#### Gate Charge Characteristics<sup>2)</sup>

Gate to source charge	Q <sub>gs</sub>		-	25	33	nC
Gate to drain charge	Q <sub>gd</sub>	$V_{\rm DD}$ =-24V, $I_{\rm D}$ =-80A, $V_{\rm GS}$ =0 to -10V	1	55	82.5	
Gate charge total	Q <sub>g</sub>	$V_{\rm GS}$ =0 to -10V	-	150	200	]
Gate plateau voltage	V <sub>plateau</sub>		-	-3.0	-	V

#### **Reverse Diode**

Diode continous forward current <sup>2)</sup>	Is	T <sub>A</sub> =25°C	-	-	-100	А
Diode pulse current <sup>2)</sup>	I <sub>S,pulse</sub>	T <sub>A</sub> =25°C	-	-	-400	
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>F</sub> =-80A	-0.6	-1	-1.2	V
Reverse recovery time <sup>2)</sup>	t <sub>rr</sub>	V <sub>R</sub> =-15V, I <sub>F</sub> =-50A, di <sub>F</sub> /dt=100A/μs	-	50	-	ns
Reverse recovery charge <sup>2)</sup>	Q <sub>rr</sub>		-	55	-	nC

<sup>&</sup>lt;sup>1)</sup> Current is limited by bondwire; with an  $R_{thJC}$  = 0.65 K/W the chip is able to carry  $I_D$ =-195A at 25°C. For detailed information see Application Note ANPS071E at www.infineon.com/optimos

<sup>&</sup>lt;sup>2)</sup> Defined by design. Not subject to production test.

 $<sup>^{3)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.

#### 1 Power dissipation

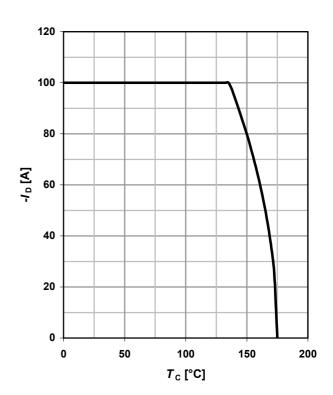
#### $P_{\text{tot}}$ =f( $T_{\text{C}}$ ); $V_{\text{GS}} \le -4 \text{ V}$

# 250 200 150 100 50 0 50 100 150 200

*T*<sub>c</sub> [°C]

#### 2 Drain current

$$I_D = f(T_C); V_{GS} \le -4 \text{ V}$$



#### 3 Safe operating area

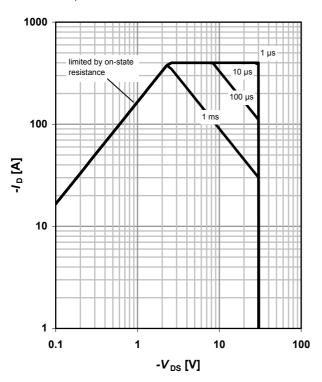
 $I_{D}=f(V_{DS}); T_{C}=25 \text{ °C}; D=0$ 

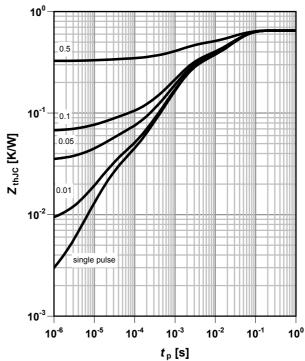
parameter: t<sub>p</sub>

### 4 Max. transient thermal impedance

 $Z_{thJC}$ =f( $t_p$ )

parameter:  $D = t_p/T$ 



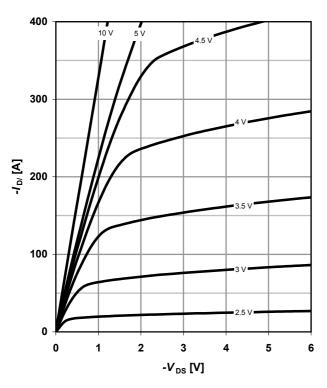




#### 5 Typ. output characteristics

 $I_D = f(V_{DS}); T_i = 25 °C$ 

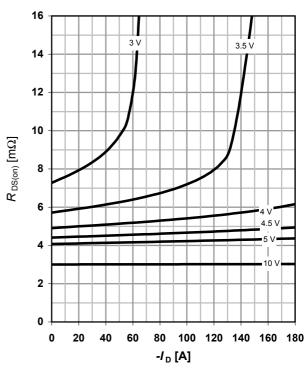
parameter:  $V_{\rm GS}$ 



#### 6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 °C$ 

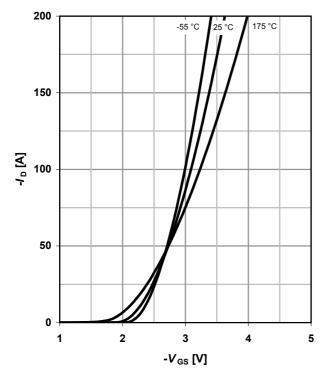
parameter:  $V_{\rm GS}$ 



#### 7 Typ. transfer characteristics

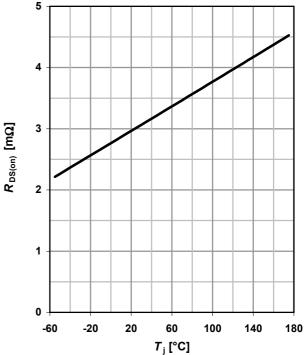
 $I_D = f(V_{GS}); V_{DS} = 4V$ 

parameter: T<sub>i</sub>



#### 8 Typ. drain-source on-state resistance

$$R_{DS(on)} = f(T_j); I_D = -80 \text{ A}; V_{GS} = 10 \text{ V}$$





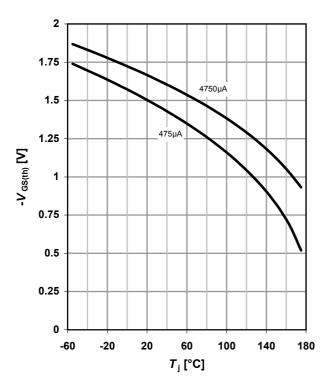
#### 9 Typ. gate threshold voltage

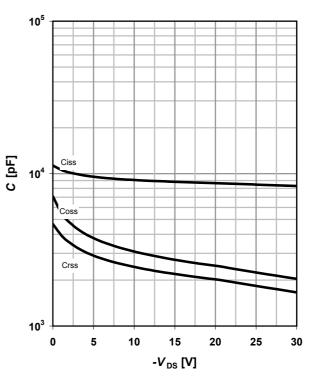
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$ 

parameter: I<sub>D</sub>

#### 10 Typ. capacitances

$$C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$$





#### 11 Typical forward diode characteristicis

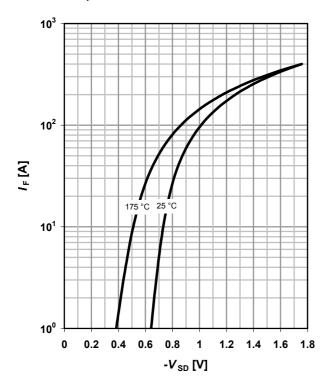
 $IF = f(V_{SD})$ 

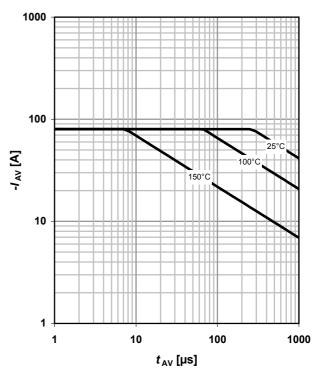
parameter: T<sub>i</sub>

#### 12 Typ. avalanche characteristics

 $I_{AV} = f(t_{AV})$ 

parameter: T<sub>i(start)</sub>







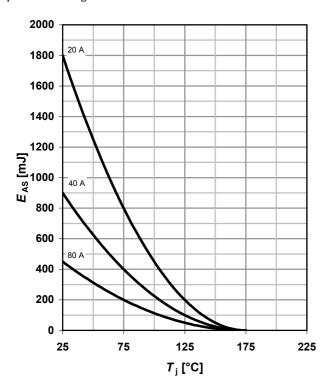
#### 13 Typical avalanche energy

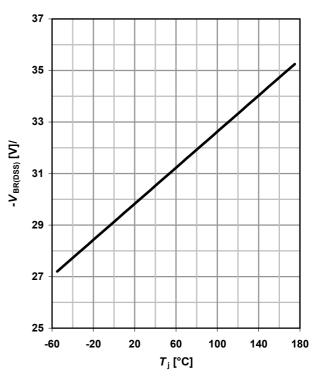
#### $E_{AS} = f(T_i)$

parameter:  $I_{\rm D}$ 

#### 14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_i); I_D = 1 \text{ mA}$$

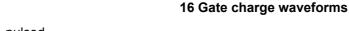


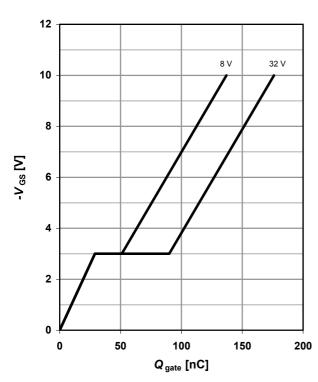


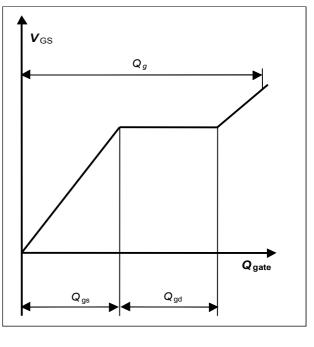
#### 15 Typ. gate charge

 $V_{GS}$  = f(Q<sub>gate</sub>);  $I_D$  = 80 A pulsed

parameter:  $V_{\rm DD}$ 









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**Revision History** 

Version	Date	Changes
Rev 1.1	25.09.2007	Type on page 1 changed from IP 100P06P3L-04 to IP 100P03PL